

Supporting Information

For

Understanding Copper Activation and Xanthate Adsorption on Sphalerite by ToF-SIMS, XPS and in-situ SECM

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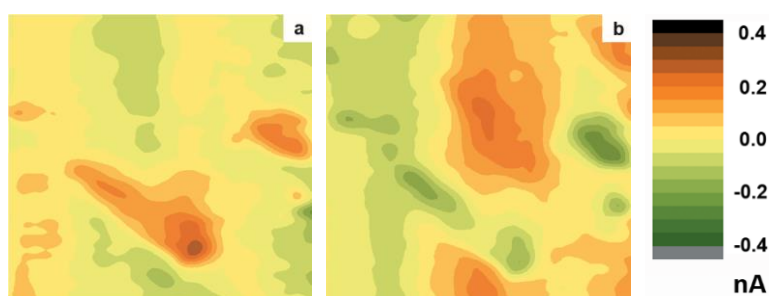


Figure S1. SECM images (a) after subtracting the current response in Figure 4a from Figure 4b, (b) subtracting the current response in Figure 4b from Figure 4c. Note positive current value in the image indicates the current increases, and negative value means the current decreases.